PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Yoel ARIELI, et al.

Serial No.: 09/829,435

Group No.: 2877

Filed: April 9, 2001

Examiner:

SPATIAL AND SPECTRAL WAVEFRONT ANALYSIS

AND MEASUREMENT

Attorney Docket No.: U 013396-8

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

FACSIMILE NO.: 703-305-4372

NO. OF PAGES: 4 ATTN: Bernadette Queen

As requested enclosed is the 1449 of December 10, 2001.

JULIAN COHEN CO LADAS & PARRY 26 WEST 61st STREET NEW YORK, N. Y. 10023

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